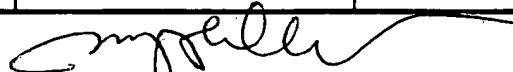| Substitute for form 1449/PTO (Revised 04/2003) **INFORMATION DISCLOSURE STATEMENT BY APPLICANT** *(Use as many sheets as necessary)*		Complete if Known	
		Application Number	PCT/GB2003/002599
		Filing Date	06/17/2003
		First Named Inventor	Hamilton
		Group Art Unit	Unknown
		Examiner Name	Unknown
Sheet	1 of 2	Attorney Docket Number	031749/286126

U. S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	Document Number — Number - Kind Code (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages of Relevant Figures Appear
pmc	1	US-5,694,356	12/02/1997	Wong et al.	
pmc	2	US-5,745,409	04/28/1998	Wong et al.	
pmc	3	US-5,748,124	05/05/1998	Rosenthal et al.	
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Examiner Initials	Cite No.	Foreign Patent Document — Country Code - Number Kind Code (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	English Language Translation Attached
pmc	5	WO 98/55880	12/10/1998	Hamida et al.		

Examiner Signature		Date Considered	1/11/06

*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Substitute for form 1449/PTO (Revised 04/2003)		Complete if Known	
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		Group Art Unit	Unknown
(Use as many sheets as necessary)		Examiner Name	Unknown
Sheet	2 of 2	Attorney Docket Number	031749/286126

OTHER DOCUMENTS

Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	English Language Translation Attached
pme	6	ZHENG ET AL.; *A Novel Test Generation Approach for Parametric Faults in Linear Analog Circuits*; 14th IEEE VLSI Test Symposium; 1996; Pages 470-475 (XP-002265465)	
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pme	16	Copy of Search Report for International Application No. PCT/GB03/02599 completed April 20, 2004	
pme	17	Copy of International Preliminary Examination Report for International Application No. PCT/GB03/02599 completed November 2, 2004	

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